

Effective scalable IEEE 1687 instrumentation network for fault management

Jutman, Artur; Shibin, Konstantin; Devadze, Sergei IEEE design & test 2013 / p. 26-35 : ill

Health management for self-aware SoCs based on IEEE 1687 infrastructure

Shibin, Konstantin; Devadze, Sergei; Jutman, Artur; Grabmann, Martin; Pricken, Robin IEEE Design & Test 2017 / p. 27-35 : ill
<https://doi.org/10.1109/MDAT.2017.2750902>

Impact of orientation on the bias of SRAM-based PUFs

Abideen, Zain Ul; Wang, Rui; **Perez, Tiago Diadami;** Schrijen, Geert-Jan; **Pagliarini, Samuel Nascimento** IEEE design & test 2023 / 1 p <https://doi.org/10.1109/MDAT.2023.3322621>